CSE 560 Computer Systems Architecture

Technology

Survey: What is Moore's Law?

What does Moore's Law state?

- A. The length of a transistor halves every 2 years.
- B. The number of transistors on a chip will double every 2 years.
- C. The frequency of a processor will double every 2 years.
- D. The number of instructions a CPU can process will double every 2 years.



Survey: What is Moore's Law?

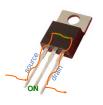
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Technology Unit Overview

- · Technology basis
 - Transistors
 - Transistor scaling (Moore's Law)
- The metrics
 - Cost
 - Transistor speed
 - Power
 - Reliability

How do the metrics change with transistor scaling? How do these changes affect the job of a computer architect?





The Transistor

Technology Generations

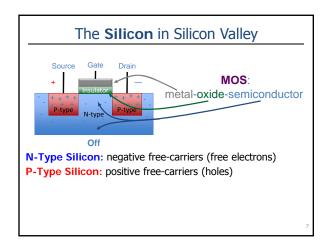
1950-1959 Vacuum Tubes

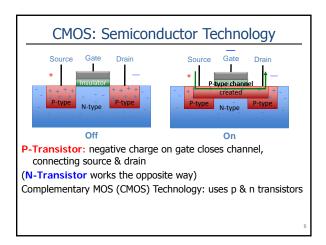
1960-1968 Transistors

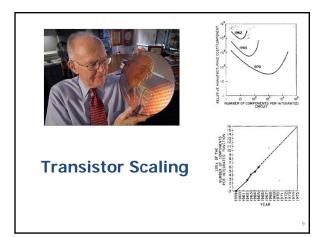
1969-1977 Integrated Circuit (multiple transistors on chip) 1978-1999 LSI & VLSI (10Ks & 100Ks transistors on chip) 2000-20xx VLSI (millions, now billions transistors on chip)

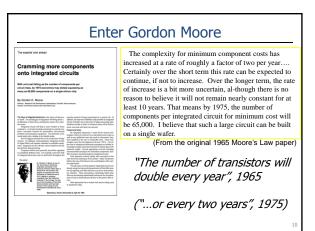












Moore's Law: Technology Scaling gate drain • Channel length: characteristic parameter (short → fast) • Aka "feature size" or "technology" • Currently: 0.010 micron (μm), 10 nanometers (nm) • Moore's Law: aka "technology scaling" • Continued miniaturization (≈ channel length) + Improves: switching speed, power/transistor, area(cost)/transistor - Reduces: transistor reliability

Moore's Law Interpreted **1975**: Moore says # of transistors doubles every 2 years David House (Intel) says due to transistors' performance improvement, performance will double every 18 months "The effects of Moore's Law and Slacking on Large Computations" (Gottbrath+) The red line denotes the amount of work completed if you start calculating now. ...If you wait some amount of time, then buy a new computer and begin the computation, Moore's law ensures that the new computer will be faster, and you will get a steeper performance curve.... At the green line ...you could start a computation now, calculate for 40 months. and get a certain amount of work done. Alternately you could go to the beach for 2 years, then come back and buy a new computer and compute for a year, and get the same amount of work done.



Cost

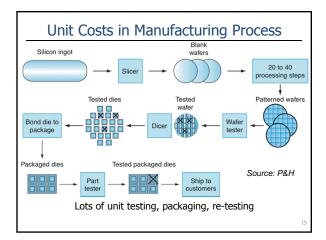
Cost

- Metric: \$
- CPU = fraction of cost, so is profit (Intel's, Dell's)

	Desktop	Laptop	Netbook	Phone
\$	\$100-\$300	\$150-\$350	\$50-\$100	\$10-\$20
% of total	10-30%	10-20%	20-30%	20-30%
Other costs	Memory, display, power supply/battery, storage, software			

- We are concerned about *chip cost*
 - Unit cost: costs to manufacture individual chips
 - Startup cost: cost to design chip, build the manufacturing facility

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Unit Cost: Integrated Circuit (IC)

- Cost / wafer is constant, f(wafer size, number of steps)
- · Chip (die) cost related to area
 - Larger chips \rightarrow fewer chips/water
 - → fewer *working* ones
 - Chip cost ~ chip areaα
 - $\alpha = 2$ to 3
 - · Why? random defects
- Wafer yield: % wafer that is chips
- Die yield: % chips that work
 - Yield is increasingly non-binary, fast vs. slow chips

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Fixed Costs

- · For new chip design
 - Design & verification: ~\$100M (500 person-years @ \$200K per)
 - Amortized over "proliferations", e.g., Xeon/Celeron cache variants
- For new (smaller) technology generation
 - ~\$3B for a new fab
 - Amortized over multiple designs
 - Amortized by "rent" from companies w/o their own fabs
- Intel's tick-tock (smaller → better)

Survey: Moore's Effect on Cost

Which of the following costs decrease as a result of transistor scaling?

- A. Cost per transistor
- B. Cost of fabrication equipment
- C. Design costs
- D. Verification costs
- E. Testing Costs

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Survey: Moore's Effect on Cost

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Q .

Transistor Speed

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Moore's Speed Effect #1: Transistor Speed

Transistor length: "process generation" 45nm = transistor gate length Source

Shrink transistor length:

- + \resistance of channel (shorter)
- + Igate/source/drain capacitance

Result: switching speed 1 linearly as gate length 1

· much of past performance gains

But 2nd-order effects more complicated

- Process variation across chip increasing
 - Some transistors slow, some fast
 - · Increasingly active research area: dealing with this

Diagrams © Krste Asanovic, MIT

Length

Drain

Bulk Si

√Width

Moore's Speed Effect #2: More Transistors

Linear shrink in each of 2 dimensions

- 180 nm, 130 nm, 90 nm, 65 nm, 45 nm, 32 nm, 22 nm, 14 nm, 10 nm, ...
- Each generation is a 1.414 linear shrink
- Results in 2x more transistors (1.414*1.414)

More transistors → increased performance

- Job of computer architect: figure out what to do with the ever-increasing # of transistors
- Examples: caches, branch predictors, exploiting parallelism at all levels

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Moore's Speed Effect #3: Psychological

Moore's Curve: common interpretation of Moore's Law

- "CPU performance doubles every 18 months"
- Self fulfilling prophecy: 2X in 18 months is ~1% per week
 - Q: Would you add a feature that improved performance 20% if it would delay the chip 8 months?
- Processors under Moore's Curve (arrive too late) fail spectacularly
 - E.g., Intel's Itanium, Sun's Millennium

Power & Energy

Power/Energy Increasingly Important

- · Battery life for mobile devices
 - Laptops, phones, cameras
- Tolerable temperature for devices without active cooling
 - Power means temperature, active cooling means cost
 - No fan in a cell phone, no market for a hot cell phone
- Electric bill for compute/data centers
 - Pay for power twice: once in, once out (to cool)
- · Environmental concerns
 - "Computers" account for growing fraction of energy consumption

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Energy & Power

Energy: total amount of energy stored/used

• Battery life, electric bill, environmental impact

Power: energy per unit time

- Related to "performance" (also a "per unit time" metric)
- Power impacts power supply, cooling needs (cost)
- Peak power vs. average power
- E.g., camera power "spikes" when you take a picture

Two sources:

- Dynamic power: active switching of transistors
- Static power: transistors leak even when inactive

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How to Reduce Dynamic Power

- Target each component: $P_{dynamic} \sim N * C * V^2 * f * A$
- Reduce number of transistors (N)
 - Use fewer transistors/gates
- Reduce capacitance (C)
 - Smaller transistors (Moore's law)
- Reduce voltage (V)
 - Quadratic reduction in energy consumption!
 - But also slows transistors (transistor speed is ~ to V)
- Reduce frequency (f)
 - Slow clock frequency MacBook Air
- Reduce activity (A)
 - "Clock gating" disable clocks to unused parts of chip
 - Don't switch gates unnecessarily

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How to Reduce Static Power

- Target each component: $P_{static} \sim N * V * e^{-Vt}$
- Reduce number of transistors (N)
 - Use fewer transistors/gates
- Reduce voltage (V)
 - Linear reduction in static energy consumption
 - But also slows transistors (transistor speed is ~ to V)
- Disable transistors (also targets N)
- "Power gating" disable power to unused parts (long time to power up)
- · Power down units (or entire cores) not being used
- $Dual V_t$ use a mixture of high and low V_t transistors (slow for SRAM)
 - Requires extra fabrication steps (cost)
- Low-leakage transistors
 - High-K/Metal-Gates in Intel's 45nm process

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Moore's Effect on Power

- + Reduces power/transistor
 - Reduced sizes and surface areas reduce capacitance (C)
- Increases power density and total power
 - By increasing transistors/area and total transistors
 - Faster transistors \rightarrow higher frequency \rightarrow more power
 - Hotter transistors leak more (thermal runaway)
- What to do? Reduce voltage [486 (5V) → Core2 (1.1V)]
 - + \ \ dynamic power quadratically, static power linearly
 - Keeping V_t the same and reducing frequency (F)
 - Lowering V_{t} and increasing leakage exponentially
 - or new techniques like high-K and dual-V $_{\! \rm T}$

Survey: Reducing Power I

Which of the following statements is false?

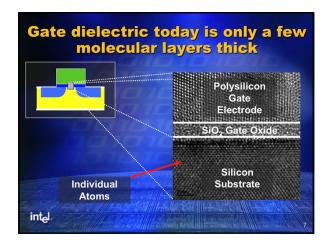
- A. A technique that lowers power consumption will also reduce energy consumption.
- B. If money were not an issue, power & energy consumption wouldn't be either.
- C. Smaller transistors leak less than larger ones.
- D. Energy usage matters for mobile devices but not for desktop computers.
- E. All of the above

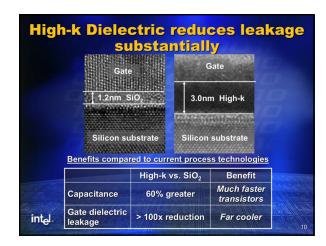
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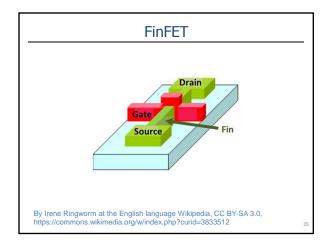
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Continuation of Moore's Law P856 P858 Px60 P1262 P1264 P1266 P1268 P1270 1st Production 1997 1999 2001 2007 2009 2011 90 nm 22 nm Generation Wafer Size 200 200 200/300 300 300 300 300 300 Cu ter-connect ΑI ΑI Cu Cu Cu Cu Strained Si Strained Si Strained Si Strained Si Si Si Channel SiO₂ Gate dielectric SiO₂ SiO₂ SiO₂ SiO₂ High-k High-k Poly-silicor Poly-Poly-Gate electrode Metal Metal Introduction targeted at this time Intel found a solution for High-k and metal gate







Survey: Reducing Power II Which of the following techniques will reduce both dynamic and static power? A. Slowing the clock frequency B. Disable the cache C. Disable the branch predictor D. Use low-leakage transistors E. All of the above

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Survey: Reducing Power II

Which of the following techniques will reduce both dynamic and static power?

- A. Slowing the clock frequency
- B. Disable the cache
- C. Disable the branch predictor
- D. Use low-leakage transistors
- E. All of the above

Reliability

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Technology Basis for Reliability

Transient faults

- A bit "flips" randomly, temporarily
- Cosmic rays etc. (more common at higher altitudes!)

· Permanent (hard) faults

- A gate or memory cell wears out, breaks and stays broken
- Temperature & electromigration slowly deform components
- Solution for both: redundancy to detect and tolerate

Moore's Bad Effect on Reliability

- Transient faults:
 - Small (low charge) transistors are more easily flipped
 - Even low-energy particles can flip a bit now
- Permanent faults:
 - Small transistors and wires deform and break more quickly
 - Higher temperatures accelerate the process

Wasn't a problem until ~10 years ago (except in satellites)

- Memory (DRAM): these dense, small devices hit first
- Then on-chip memory (SRAM)
- Logic is starting to have problems...

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Moore's Good Effect on Reliability

- Scaling makes devices less reliable
- + Scaling increases device density to enable redundancy
- Examples
 - Error correcting code for memory (DRAM), \$s (SRAM)
 - Core-level redundancy: paired-execution, hot-spare, etc.
 - Intel's Core i7 (Nehalem) uses 8 transistor SRAM cells
 - Versus the standard 6 transistor cells
- · Big open questions
 - Can we protect logic efficiently? (w/o 2-3x overhead)
 - · Can architectural techniques help hardware reliability?
 - Can software techniques help?

Summary

Moore's Law in the Future

- Won't last forever, approaching physical limits
 - But betting against it has proved foolish in the past
 - Likely to "slow" rather than stop abruptly
- Transistor count will likely continue to scale
 - "Die stacking" is on the cusp of becoming main stream
 - · Uses the third dimension to increase transistor count
- But transistor performance scaling?
 - Running into physical limits
 - Example: gate oxide is less than 10 silicon atoms thick!
 - Can't decrease it much further
 - · Power is becoming a limiting factor

Moore's Law & Chicken Little

Appears in the Proceedings of the 27th Annual International Symposium on Computer Architecture

Clock Rate versus IPC: The End of the Road for Conventional Microarchitectures

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Abstract

The doubling of microprocess preference every three years has been the result of two facts: more treasitions per dop and superinteen realing of the processor clock with relevology generation. Our results show that, are both diminishing deprevenents in Celes Aces are all power wite scalcines and the contract of t

scaling stargets and two microarchitecture scaling strategies: pipeline scaling and capacity scaling. We find that no scaling strategy permits annual performance increasing to better than 12.5% which is for women than ne past decade's annualized rate of 50% per year. We find that the ate of clock speed improvement must soon drop to scaling linearly

Compensating for the above clock growth by increasing susinated IPC proportionally will be difficult. Wire delays will limit the ability of conventional microarchitectures to improve instruction throughput. Microprocessor cores will loom face a new constraint, one in which they are communication bound on the die intented of capacity bound. As features tizes which, and wires become clower relative to logic, the amount of state that can be accessed in sating clock cycle will crease to grow, and will eventually begin single clock cycle will crease to grow, and will eventually begin by the mount of state reachable in a cycle, not by the number of transition that can be manufactured on a click.

For conventional microarchitectures implemented in future

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Summary of Device Scaling

- + Reduces unit cost
 - But increases startup cost
- + Increases performance
 - · Reduces transistor/wire delay
 - Gives us more transistors with which to increase performance
- + Reduces local power consumption
 - Quickly undone by increased integration, frequency
 - Aggravates power-density and temperature problems
- Aggravates reliability problem
 - + But gives us the transistors to solve it via redundancy